

# ECEN474: (Analog) VLSI Circuit Design

## Fall 2011

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### Lecture 13: Noise



Sebastian Hoyos  
Analog & Mixed-Signal Center  
Texas A&M University

# Agenda

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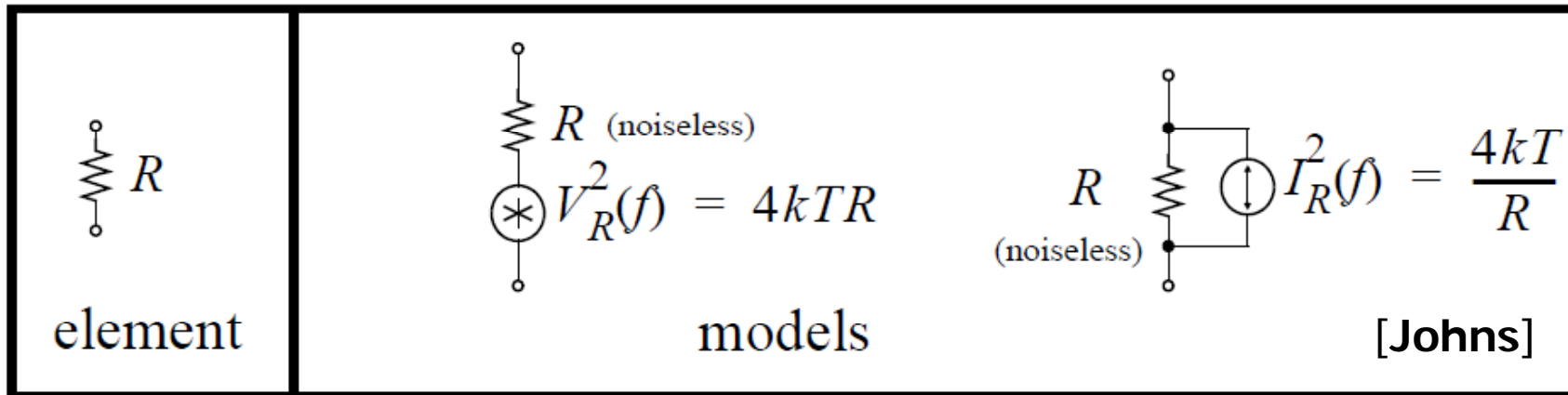
- MOSFET Noise
- Filtered Noise
- OTA Noise Example

# Resistor Noise Model

- An equivalent voltage or current generator can model the resistor thermal noise

$$V_{Rn}^2 = P_n R = 4kTR\Delta f$$

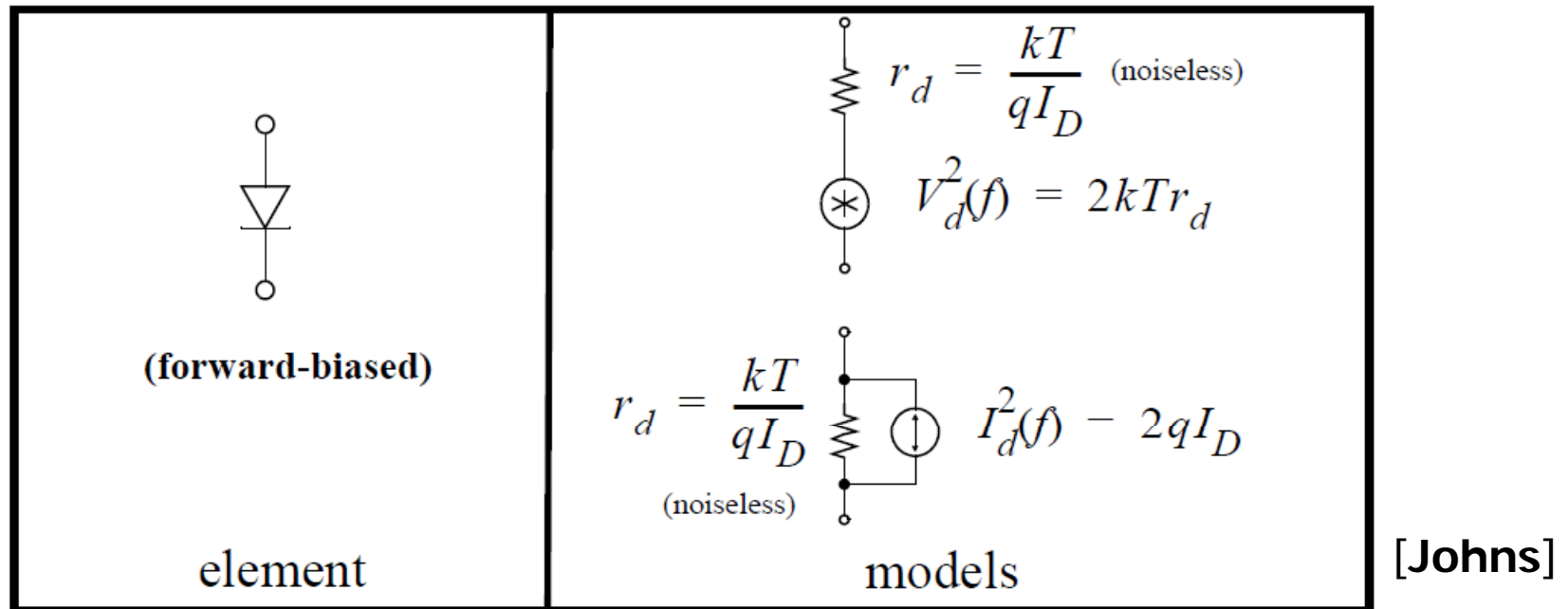
$$I_{Rn}^2 = \frac{P_n}{R} = \frac{4kT}{R} \Delta f$$



- Recall the PSD is white (uniform w/ frequency)

# Diode Noise Model

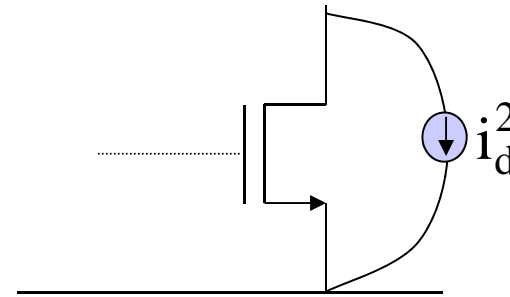
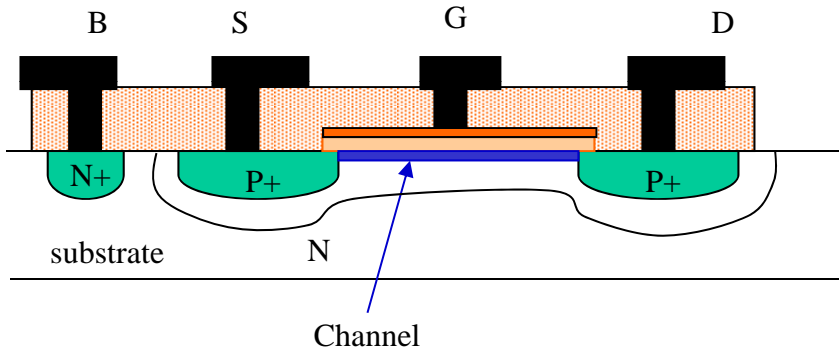
- Shot noise in diodes is caused by pulses of current from individual carriers in semiconductor junctions
- White spectral density



- Where  $q = 1.6 \times 10^{-19} \text{C}$  and  $I_D$  is the diode DC current

## Thermal Noise

=> Spectral Density of the thermal noise drain current (CMOS transistor biased @ linear region)

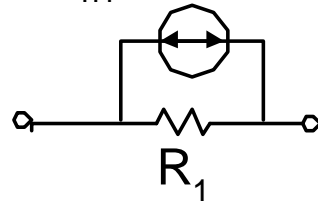


**Transistor**

$$i_d^2 = \frac{4kT}{R_{DS}}$$

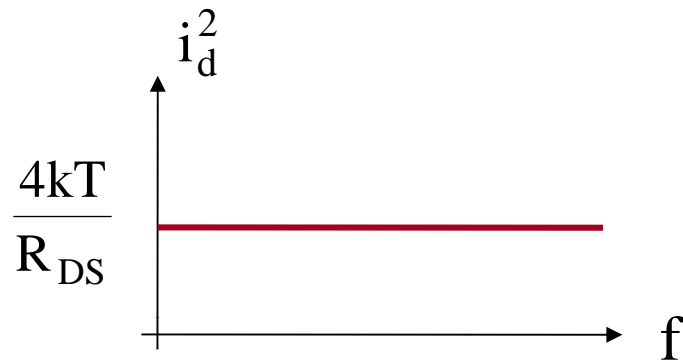
**Resistor**

$$i_{n1}^2 = 4kT/R_1$$



$$R_{DS} \cong \frac{1}{\mu C_{ox} \frac{W}{L} (V_{GS} - V_T - V_{DS})}$$

## White Noise



@ Triode region

$$i_d^2 = \left[ 4kT\mu C_{ox} \left[ \frac{W}{L} \right] \left[ V_{GS} - V_T - V_{DS} \right] \right]$$

Low current noise  $\Rightarrow W/L \downarrow \Rightarrow g_m$  or  $g_o \downarrow$

@ Saturation

$$g_o = \frac{1}{R_{DS}} \rightarrow \frac{2}{3} g_m$$

$$i_d^2 = \frac{8}{3} kT g_m$$

$$\Rightarrow i_d^2 = \left( \frac{8kT}{3} \right) (\mu C_{ox}) \left( \frac{W}{L} \right) (V_{GS} - V_T)$$

# MOSFET 1/f (Flicker) Noise

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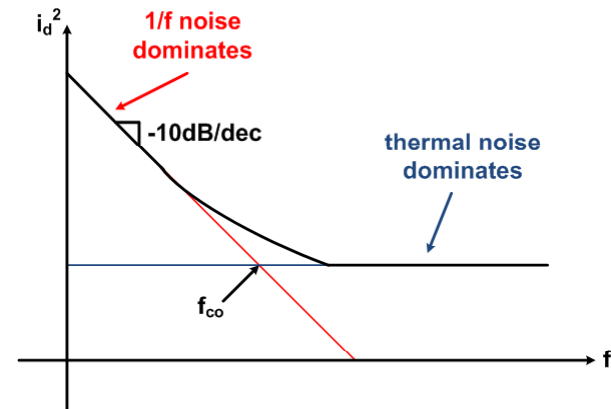
- Caused by traps near Si/SiO<sub>2</sub> interface that randomly capture and release carriers

$$i_d^2(f) = \frac{K_F g_m^2}{WLC_{ox}f}$$

- $K_F$  is strongly dependent on the technology

# 1/f Noise Corner Frequency

- This is the frequency at which the flicker noise density equals the thermal noise density



$$\frac{K_F g_m^2}{WLC_{ox} f_{co}} = 4kT\gamma g_m$$

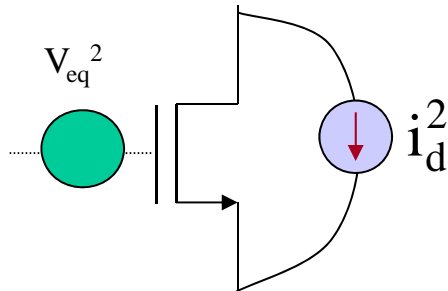
$$f_{co} = \frac{K_F}{4kT\gamma C_{ox}} \frac{g_m}{WL} = \frac{K_F}{4kT\gamma C_{ox}} \frac{1}{L} \left( \frac{g_m}{I_D} \right) \left( \frac{I_D}{W} \right)$$

- For a given  $g_m/I_D$  (which sets  $I_D/W$ ), the only way to reduce  $f_{co}$  is to use longer channel devices



# Output and input referred noise

**Current noise is the real one**      Thermal Noise       $i_d = g_m V_{gs}$   
 $i_d^2 = g_m^2 V_{gs}^2$   
**Voltage noise representation is an artifact to facilitate system analysis**       $\Rightarrow V_{gseq}^2 = \frac{8 kT}{3 g_m}$

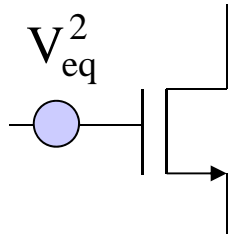


Flicker Noise       $i_d^2 = \frac{K_F g_m^2}{WLC_{ox} f}$

Referred to the input       $v_{eq}^2 = \frac{K_F g_m^2}{WLC_{ox} f} \frac{1}{g_m^2}$

$$v_{eq}^2 = \frac{K_F}{C_{ox}} \left( \frac{1}{WL} \right) \left( \frac{1}{f} \right)$$

## Equivalent input referred voltage noise



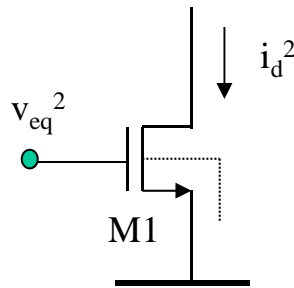
$$V_{eq}^2 = \frac{i_{dth}^2 + i_{df}^2}{g_m^2}$$

Equivalent input referred noise voltage means that all **current noise sources are accounted as drain current and represented by an “equivalent” noise voltage at transistor gate**

$$V_{eq}^2 = \frac{8 kT}{3 g_m} + \frac{K_F}{C_{ox}} \frac{1}{WL} \frac{1}{f}$$

$$V_{eq\text{total}} \text{ (RMS)} = \sqrt{\int_{BW} v_{eq}^2(f) df}$$

## NOISE COMPONENTS (values provided are for a 0.8 μm technology)



Noise density (V<sup>2</sup>/Hz)

$$V_{eq}^2 = V_{th}^2 + V_{1/f}^2$$

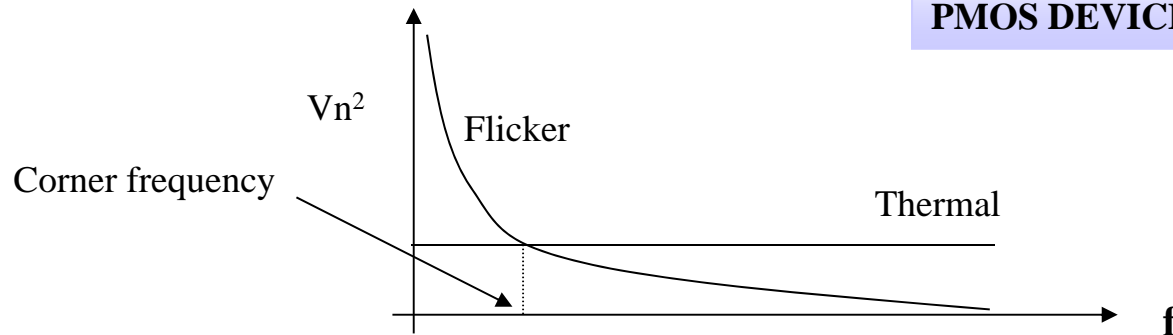
$$V_{eq}^2 = \frac{8 kT}{3 g_m} df + \frac{K_F}{WLC_{OX}f} df$$

Spice model

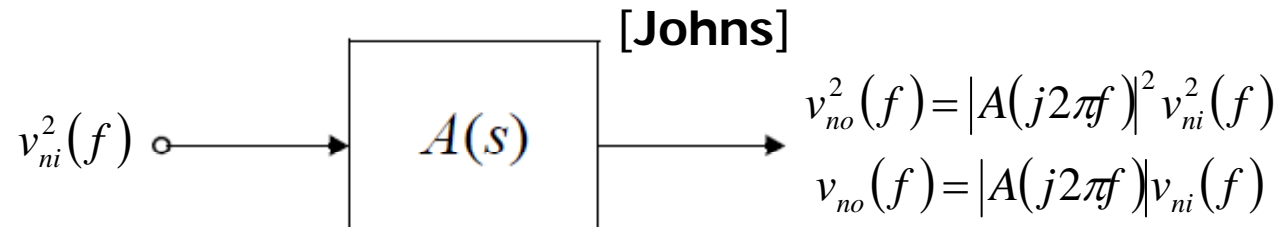
$$\frac{K_F}{C_{OX}} = 9.8 \times 10^{-9} \text{ V}^2 / \mu\text{m} - \text{Hz (NMOS)}$$

$$= 0.5 \times 10^{-9} \text{ V}^2 / \mu\text{m} - \text{Hz (PMOS)}$$

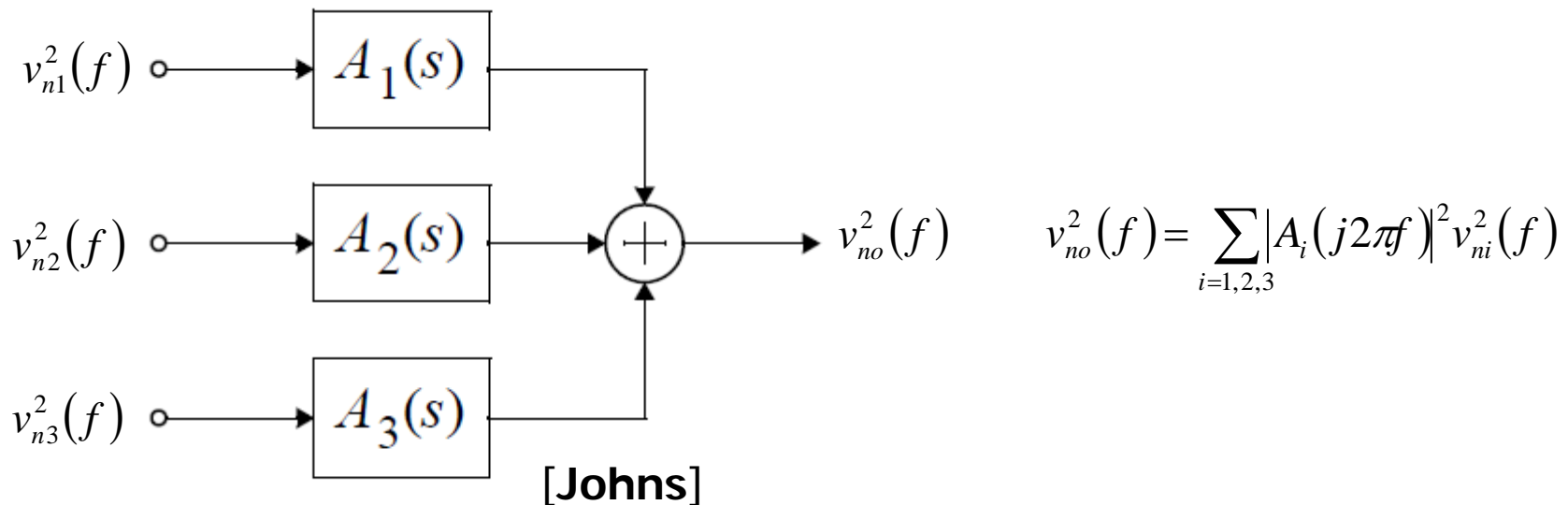
**FOR LOW-FREQUENCY APPLICATIONS,  
WHEREIN 1/F NOISE IS DOMINANT,  
PMOS DEVICES MUST BE USED.**



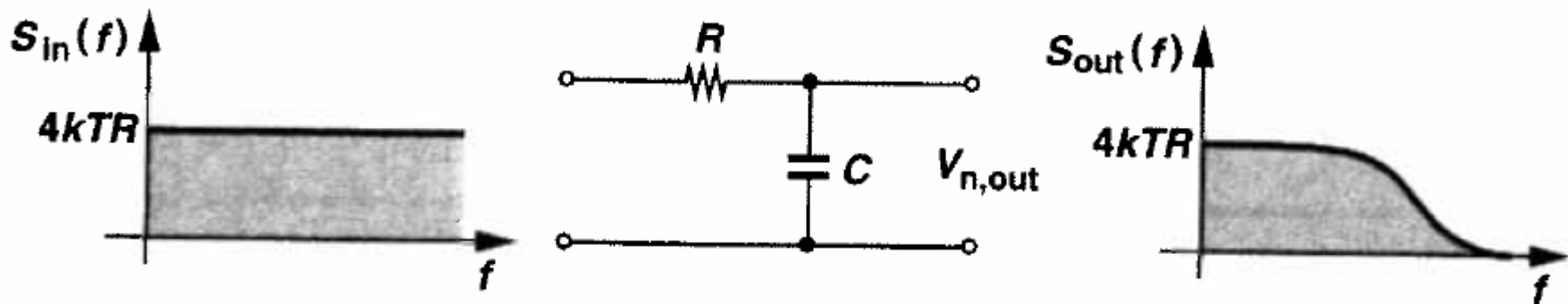
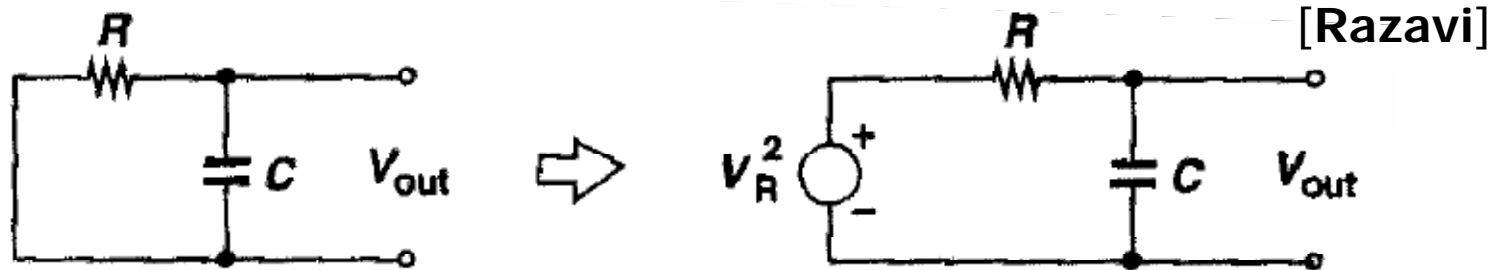
# Filtered Noise



- Noise output spectral density is a function only of the magnitude of the transfer function, and not its phase
- With multiple uncorrelated noise sources, combined output is also uncorrelated

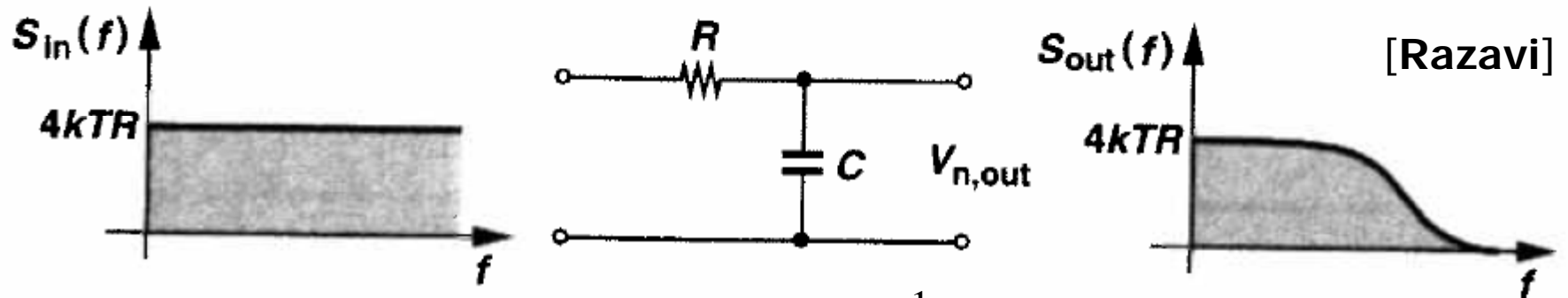


# First-Order RC Circuit Example



What is the total output noise power?

# First-Order RC Circuit Example



$$A(s) = \frac{v_{out}}{v_R}(s) = \frac{1}{1 + sRC}$$

$$v_{out}^2(f) = |A(j2\pi f)|^2 v_R^2(f) = \frac{1}{1 + 4\pi^2 f^2 R^2 C^2} 4kTR$$

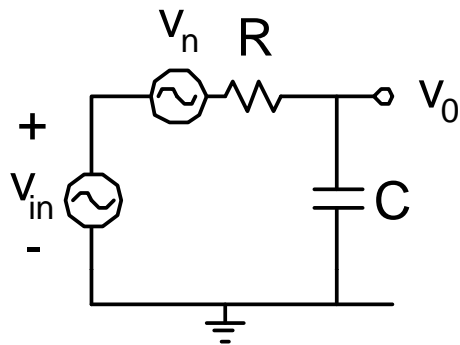
To calculate Total Noise Power integrate over all frequencies

$$v_{out}^2 = \int_0^{\infty} \frac{4kTR}{1 + 4\pi^2 f^2 R^2 C^2}$$

Using  $\int \frac{dx}{x^2 + 1} = \tan^{-1} x$

$$v_{out}^2 = \frac{2kT}{\pi C} \tan^{-1}(2\pi fRC) \Big|_{f=0}^{f=\infty} = \frac{2kT}{\pi C} \left[ \frac{\pi}{2} - 0 \right] = \frac{kT}{C}$$

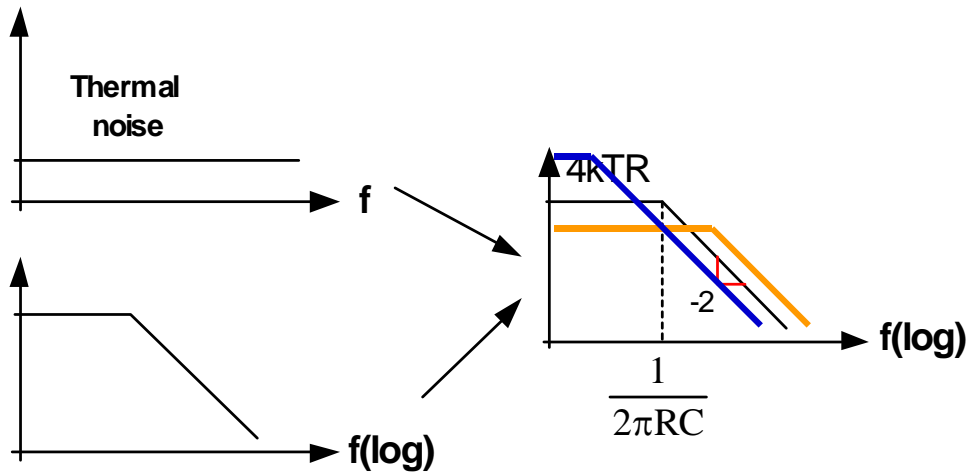
## Noise is generated by R but integrated noise is function of C (??)



$$v_{total}^2 = \int_0^{\infty} \left( \left( \frac{1}{1 + (\omega RC)^2} \right) (4kTR) \right) df = \frac{kT}{C}$$



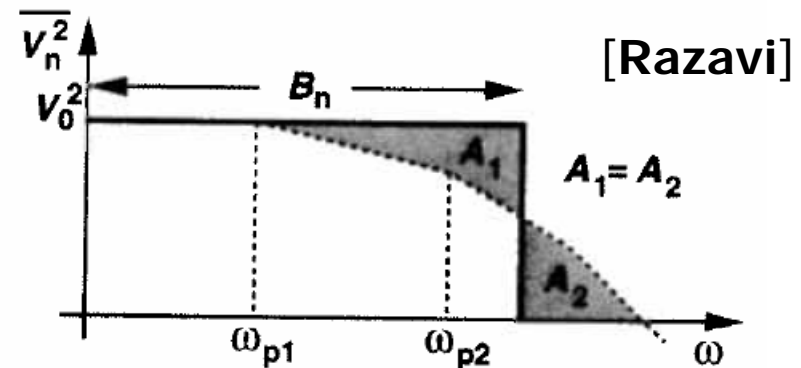
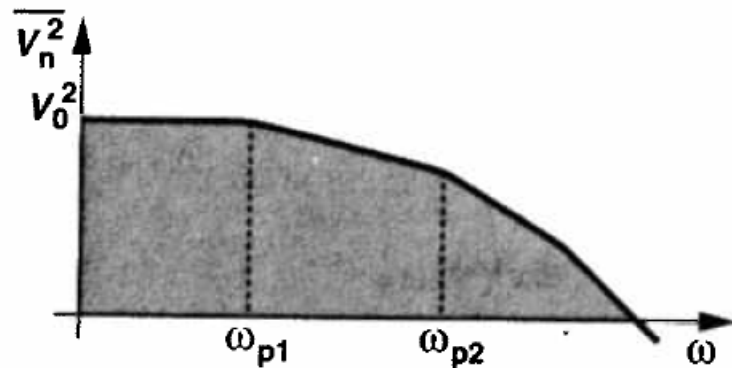
To get more insight, lets have a closer look on the operations!



Notice that:

When R increases thermal noise increases too but the corner frequency decreases, leading to a constant area under the curves!

# Noise Bandwidth



- The noise bandwidth is equal to the frequency span of a brickwall filter having the same output noise rms value

$$v_0^2 B_n = \int_0^{\infty} v_{no}^2 df$$

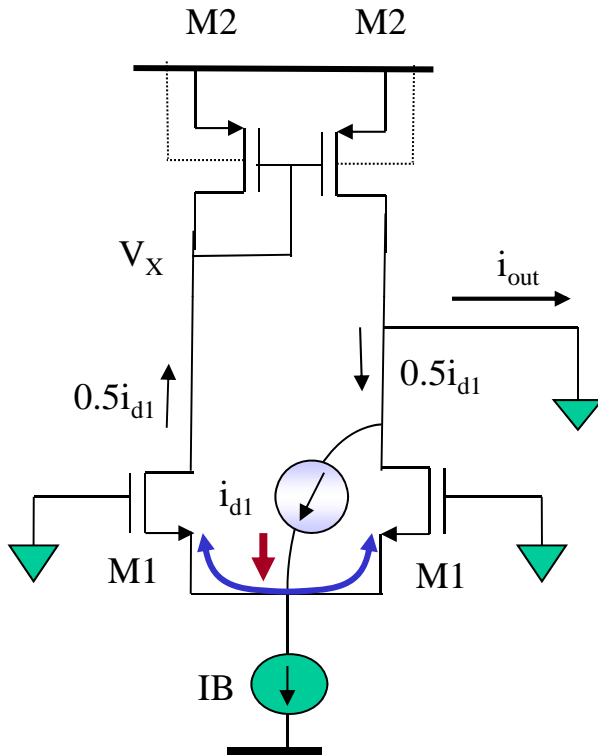
For a first - order filter  $B_n = \frac{\pi}{2} \omega_p$

Validating with previous slides derivation :

$$\text{Total Noise Output} = v_0^2 B_n = (4kTR) \left( \frac{\pi}{2} \right) \left( \frac{1}{2\pi RC} \right) = \frac{kT}{C}$$



# Output referred noise: Take advantage of SYMMETRIES!



Noise injected into the common-source node equally splits into the two branches

## Output referred current noise density

**Superposition: Every transistor contributes; consider one at the time.**

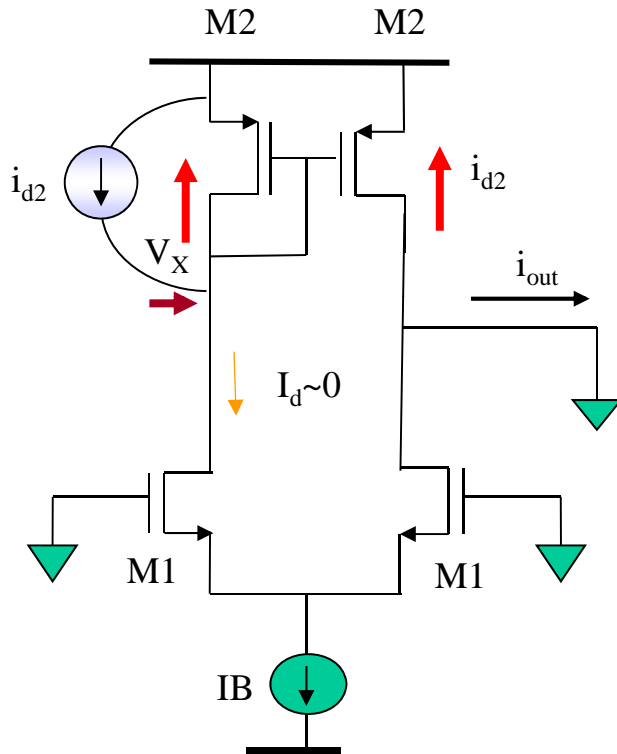
**Analysis: You can use standard circuit analysis techniques but at the end of the day you have to consider POWER.**

**Output noise density: Each noise component represent the RMS value of random uncorrelated noise! Then add the power noise components**

$$i_{out1}^2 = \frac{8}{3} kTg_{m1}$$



# Output referred noise: Take advantage of SYMMETRIES!



Noise injected into the common-source node equally splits into the two branches

Noise due to the current source is mainly common-mode noise

Output referred current noise density due to the P-type devices:

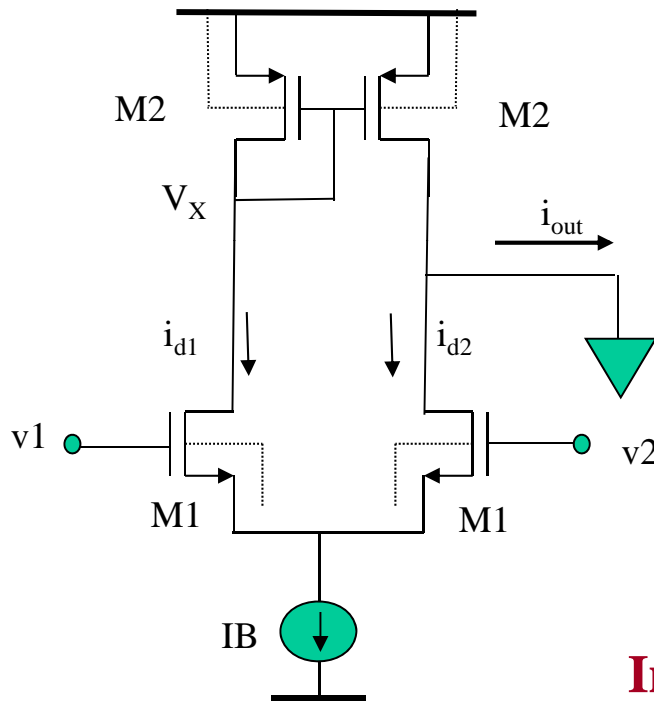
Left hand side transistor:

$$i_{out2}^2 \cong i_{d2}^2 = \frac{8}{3} kT g_{m2}$$

Right hand side transistor

$$i_{out2}^2 = \frac{8}{3} kT g_{m2}$$

# Output and input referred noise



Output referred current noise density

$$i_{\text{out}}^2 = 2 \left( \frac{8}{3} kT g_{m1} \right) + 2 \left( \frac{8}{3} kT g_{m2} \right)$$

Input referred noise density ( $V^2/\text{Hz}$ )

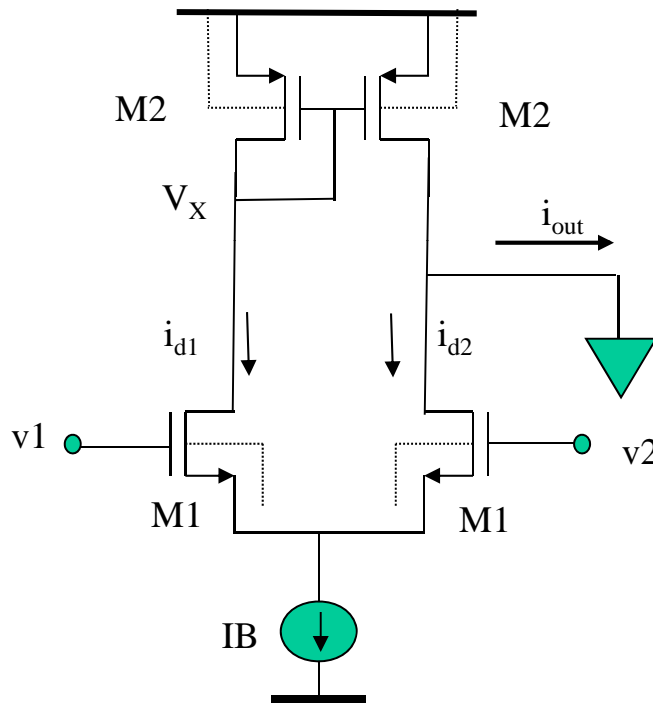
$$V_{\text{in,eq}}^2 = 2 \left( \frac{8}{3} \frac{kT}{g_{m1}} \right) + 2 \left( \frac{8}{3} \frac{kT}{g_{m1}} \frac{g_{m2}}{g_{m1}} \right)$$



**In this case, noise due to the current source is mainly common-mode noise**

**Be careful because this is not always the case!**

# Integrated Input referred noise



Input referred thermal noise density ( $V^2/Hz$ )

$$V_{in,eq}^2 = 2 \left( \frac{8 kT}{3 g_{m1}} \right) + 2 \left( \frac{8 kT}{3 g_{m1}} \frac{g_{m2}}{g_{m1}} \right)$$

Input referred noise level (volts)

$$\text{Noise}(V_{RMS}) = \sqrt{\int_{BW} V_{in,eq}^2 df}$$

Example: for thermal noise, the noise level becomes  
(assuming a single-pole system)

$$\text{Noise}(V_{RMS}) = \sqrt{\frac{16kT}{3}} \sqrt{\frac{1}{g_{m1}}} \sqrt{1 + \frac{g_{m2}}{g_{m1}}} \left( \sqrt{\frac{\pi}{2}} BW \right)$$

**I should advise you to use:**

$$\text{Noise}(V_{RMS}) \cong \sqrt{\frac{8kT}{g_{m1}}} \sqrt{1 + \frac{g_{m2}}{g_{m1}}} \left( \sqrt{BW} \right) \quad 4kT \approx 16 \times 10^{-21} \text{ coul.V}$$

# Next Time

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- OTAs